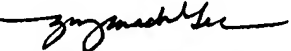
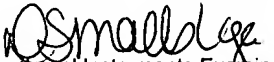


Issue Classification

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,149	CHEN, JINZU	
Examiner	Art Unit	
Lee Y Quach	2875	

ISSUE CLASSIFICATION													
ORIGINAL						CROSS REFERENCE(S)							
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
362		633			362	634							
INTERNATIONAL CLASSIFICATION													
F	2	1	V	8/00									
				/									
				/									
				/									
				/									

(Assistant Examiner) (Date)		 Y. MY QUACH-LEE PRIMARY EXAMINER (Primary Examiner)		10/25/05 (Date)		Total Claims Allowed: 15	
 (Legal Instruments Examiner)		10/27/05 (Date)		O.G. Print Claim(s) 1		O.G. Print Fig. 2A	

[illegible]